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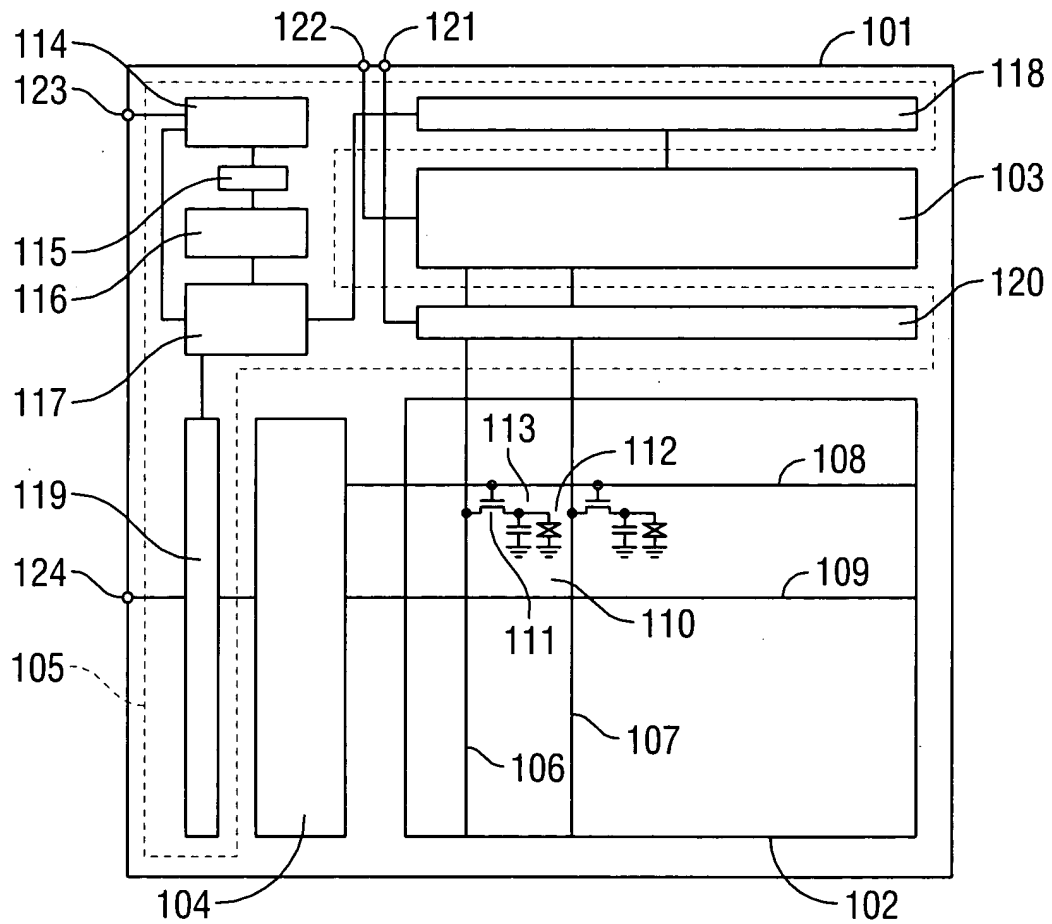


FIG. 1

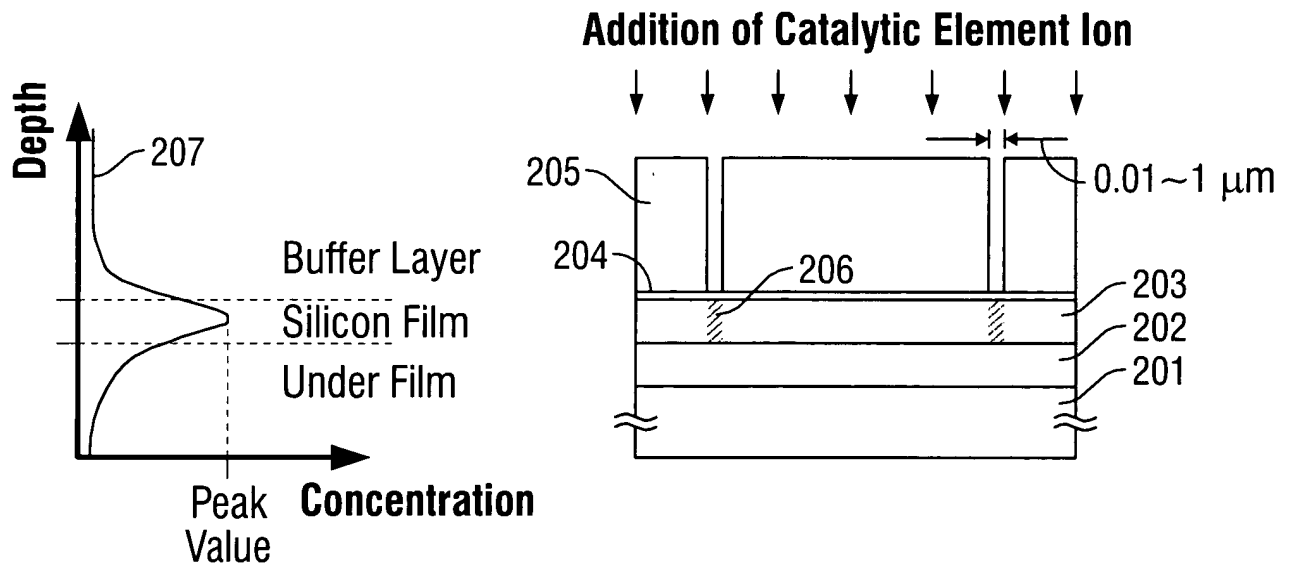


FIG. 2

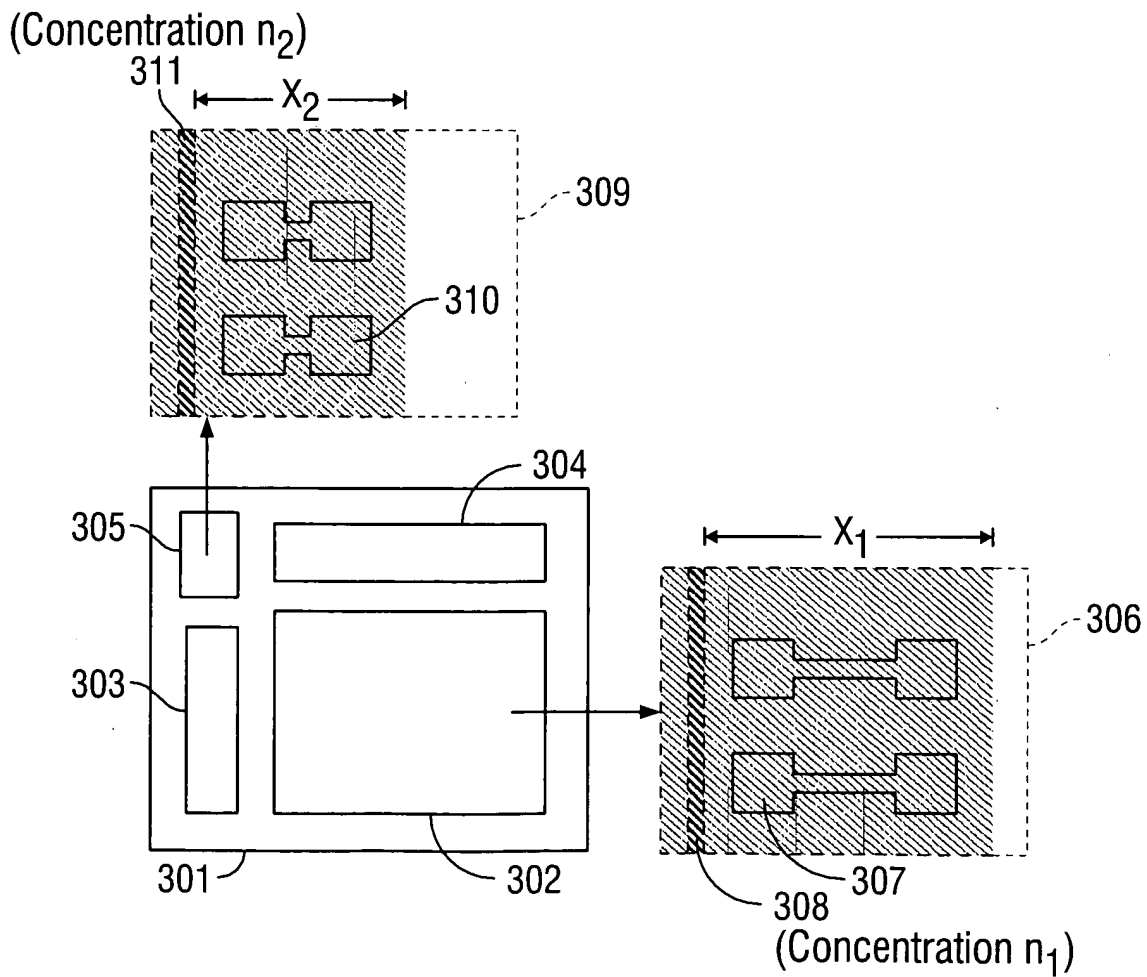


FIG. 3

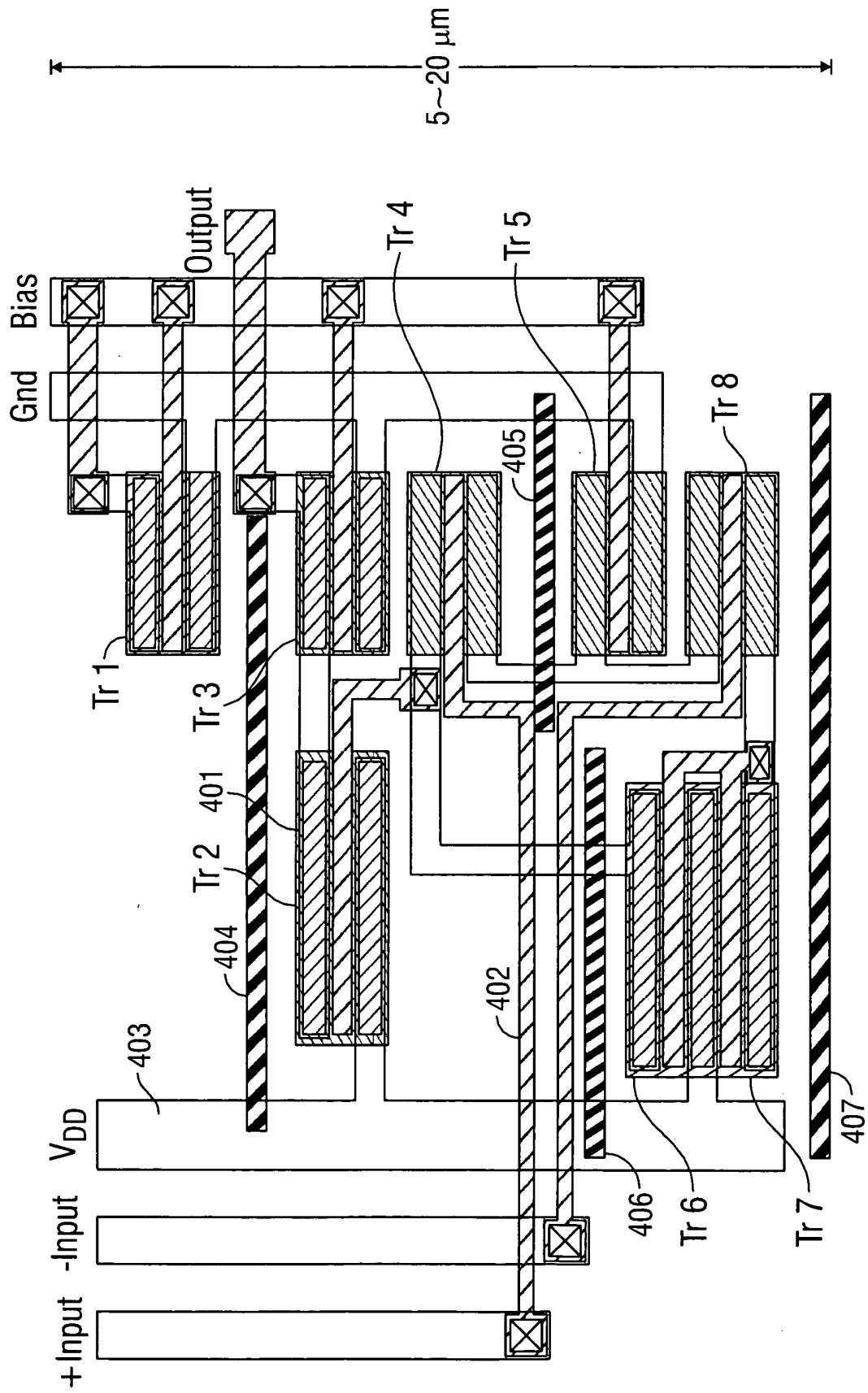


FIG. 4A

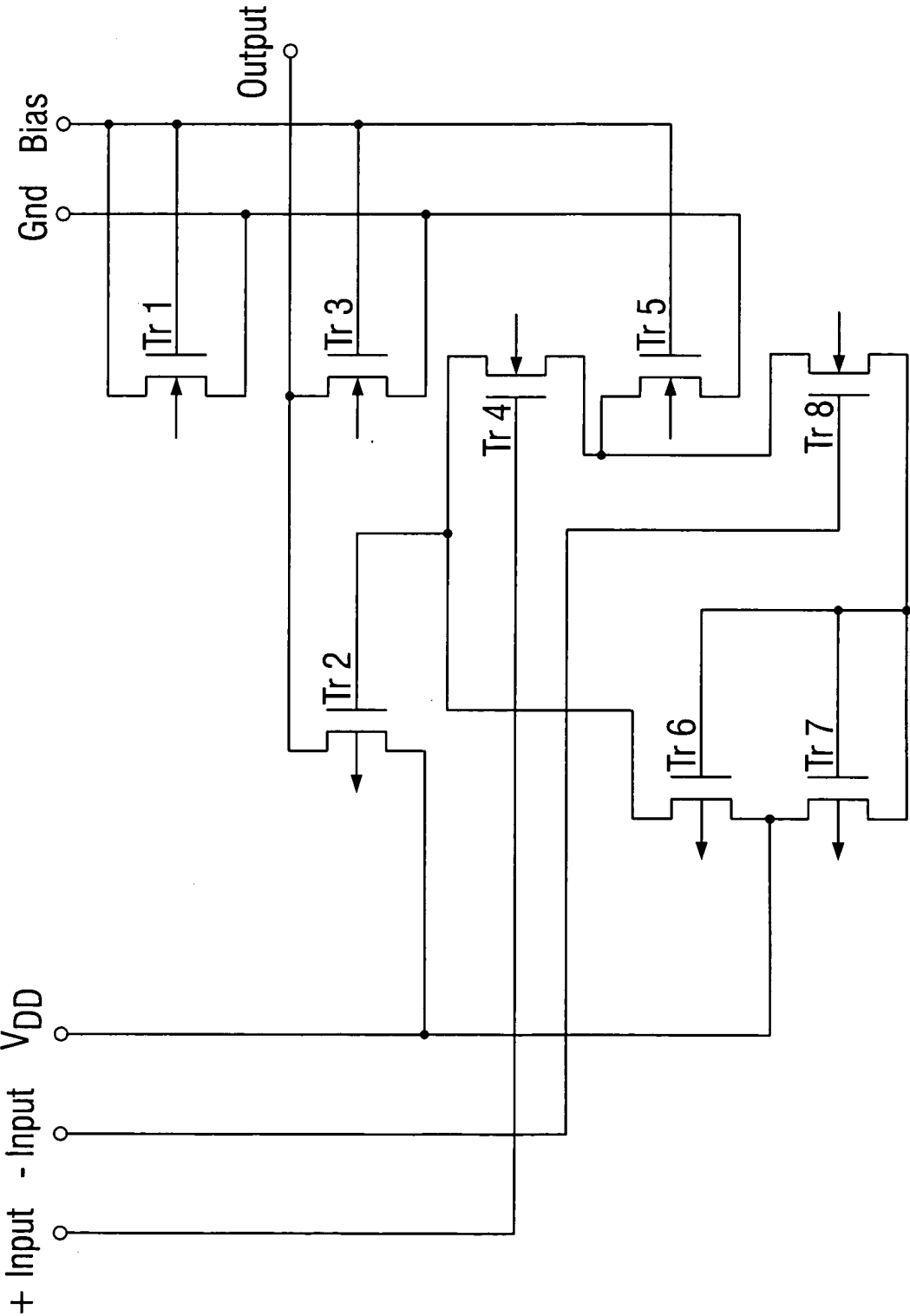
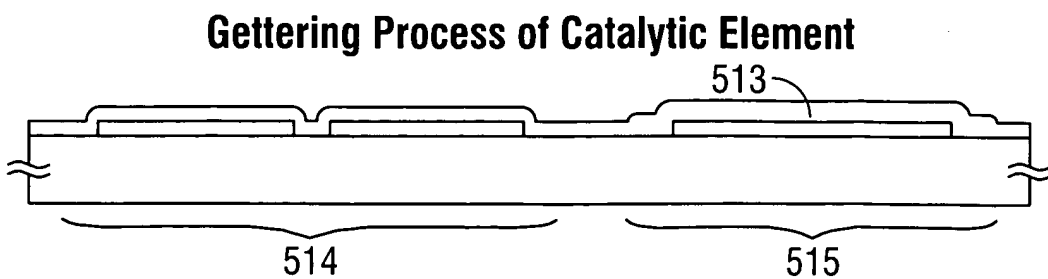
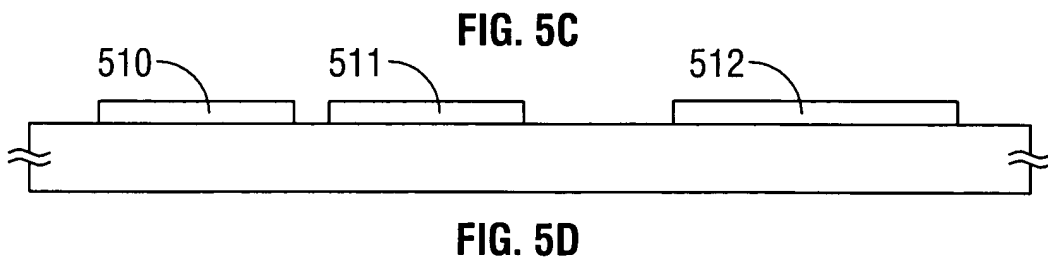
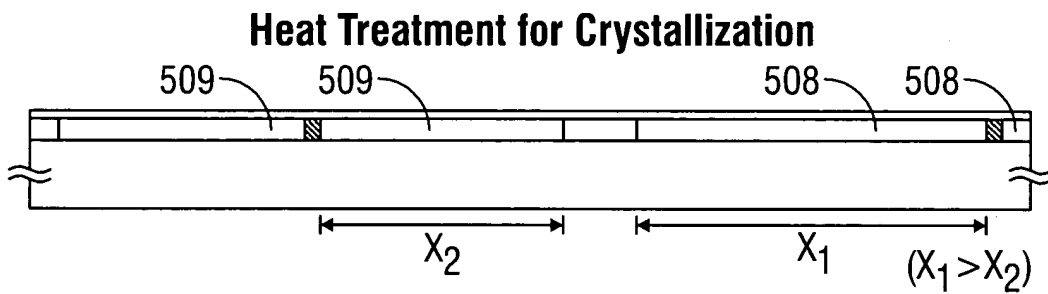
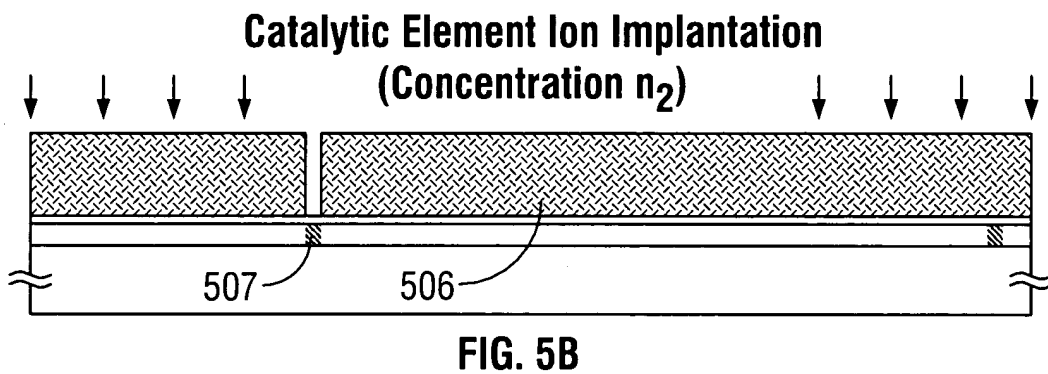
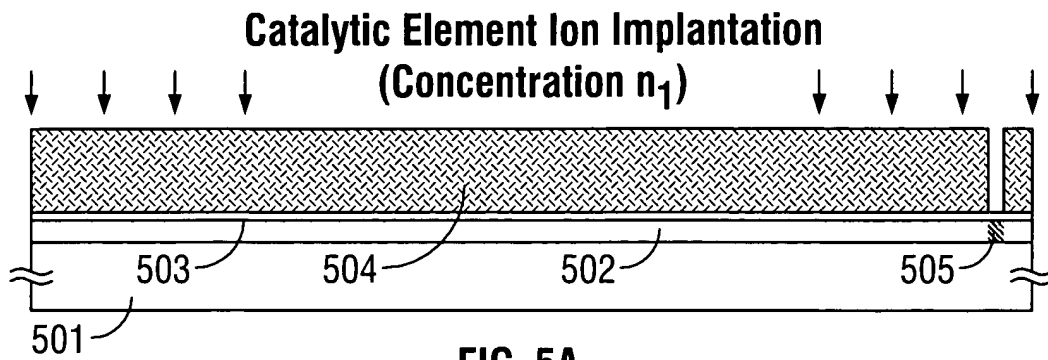


FIG. 4B



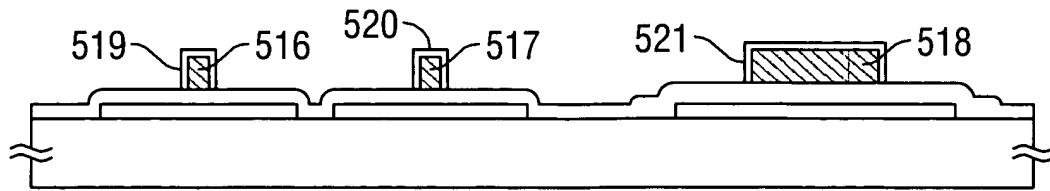


FIG. 6A

**Addition of Impurity Ion for Giving N-Type
 (Formation of n^- Region)**

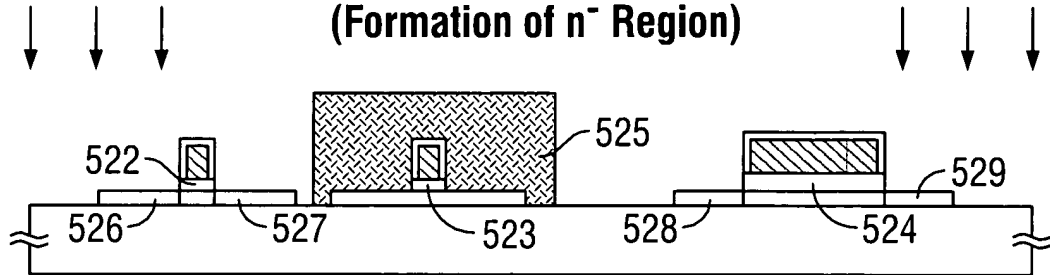


FIG. 6B

**Addition of Impurity Ion for Giving P-Type
 (Formation of p^- Region)**

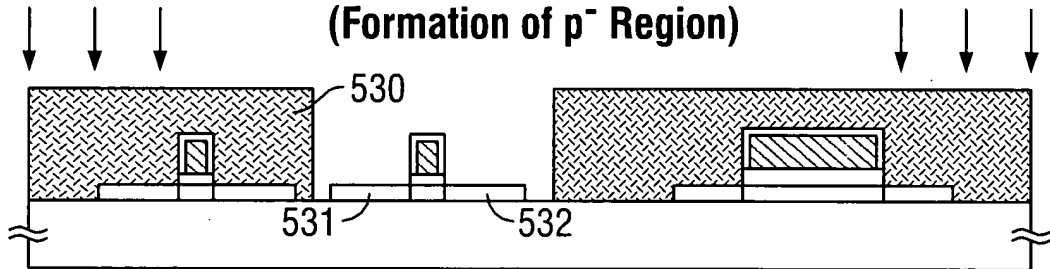


FIG. 6C

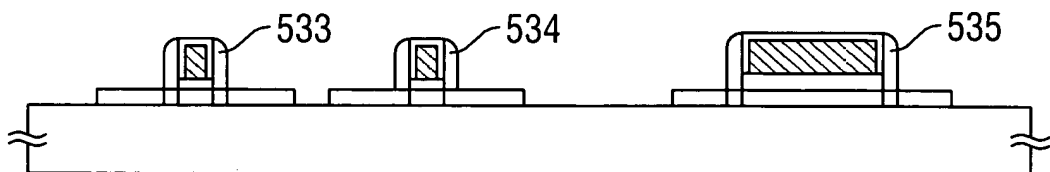


FIG. 6D

**Addition of Impurity Ion for Giving N-Type
 (Formation of n^+ Region)**

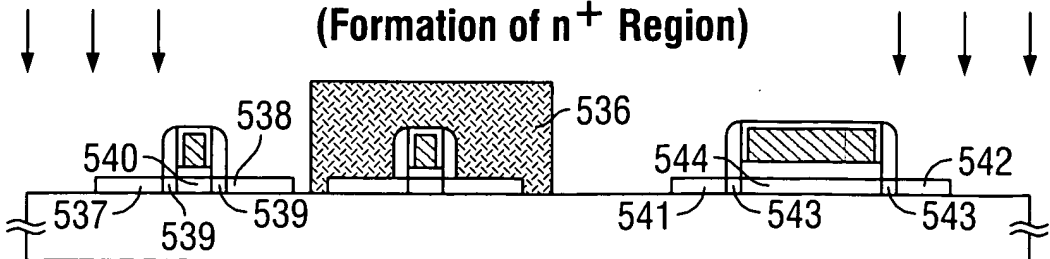


FIG. 6E

Addition of Impurity Ion for Giving P-Type (Formation of p^+ Region)

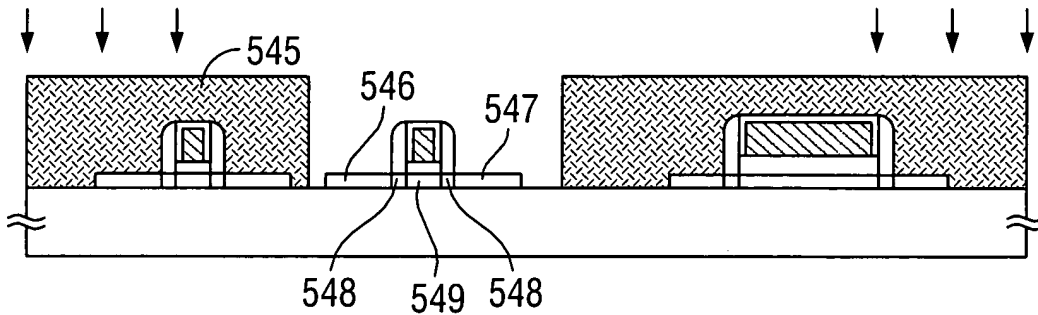


FIG. 7A

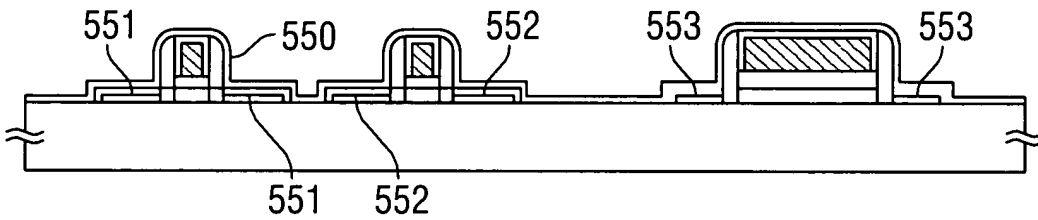


FIG. 7B

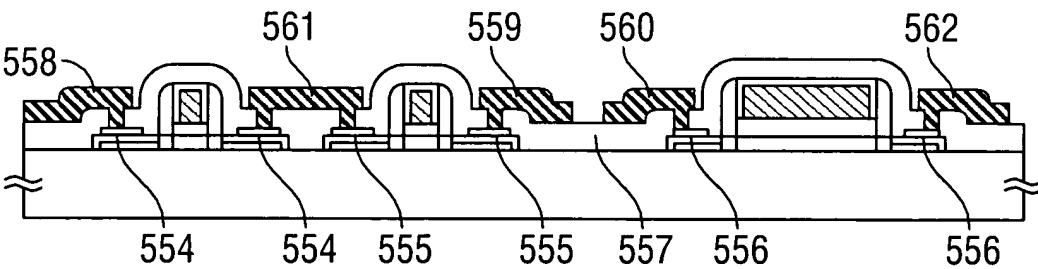
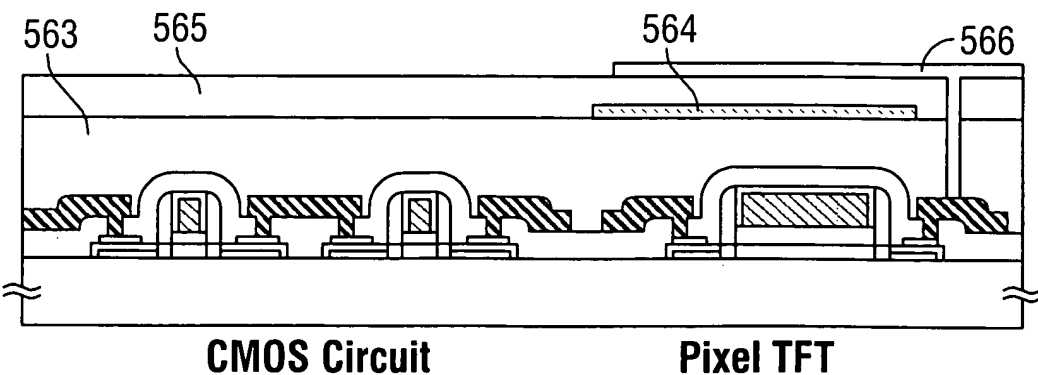


FIG. 7C



CMOS Circuit

Pixel TFT

FIG. 7D



FIG. 8

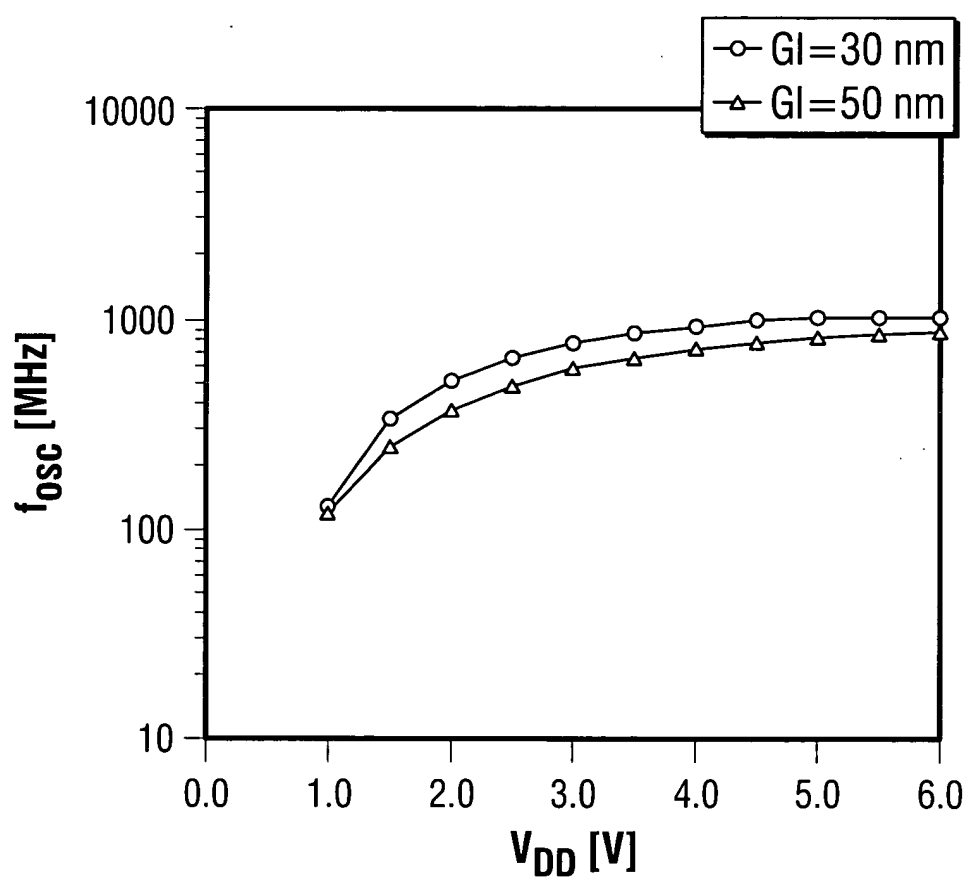


FIG. 9

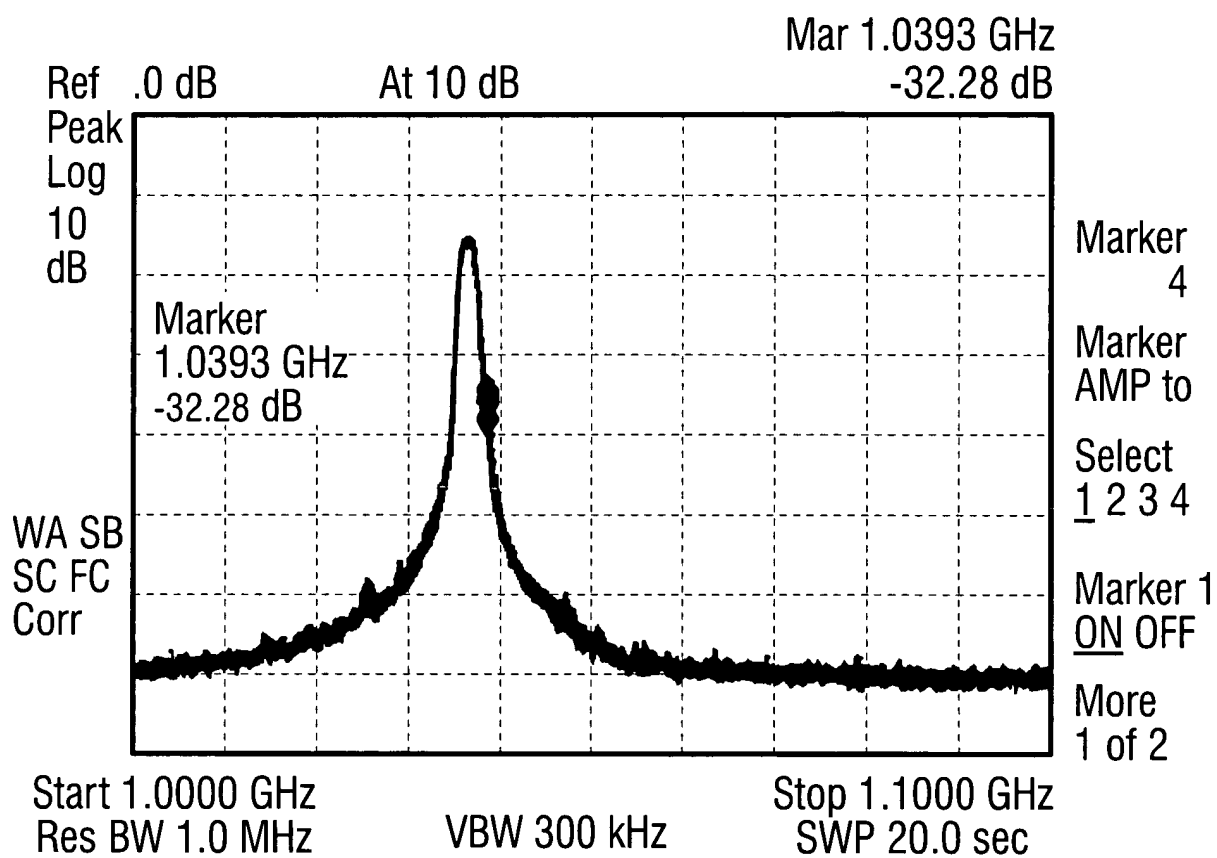


FIG. 10

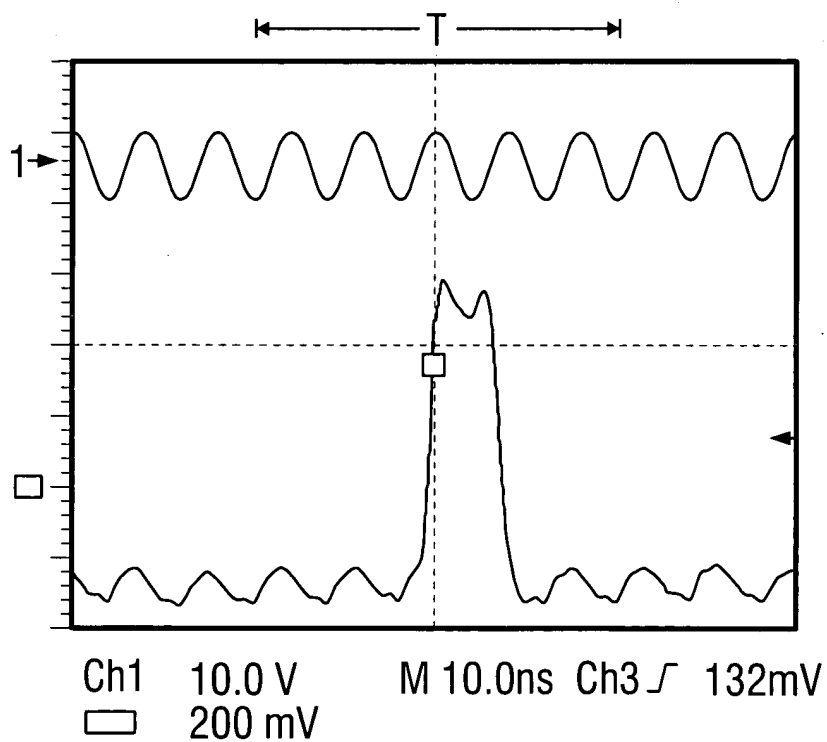
T_{pk} Run: 5.00GS/s ET Average

FIG. 11

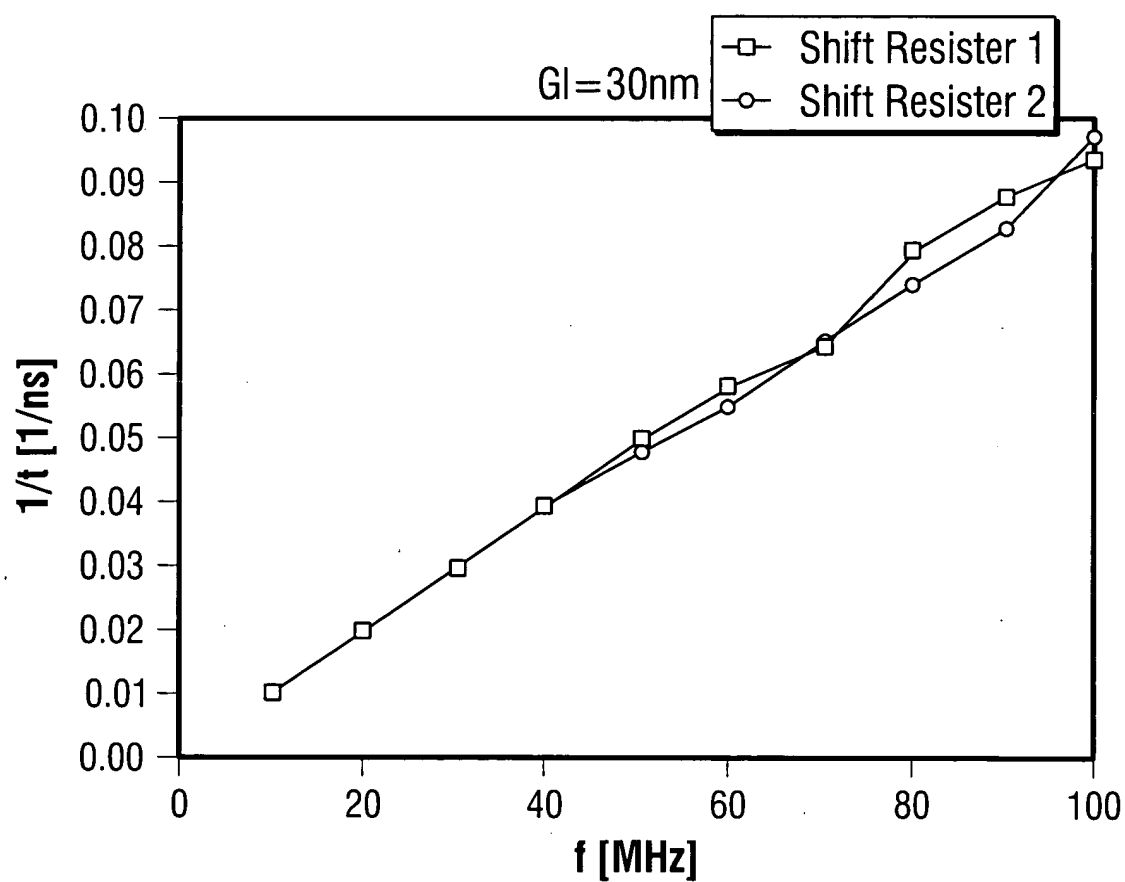


FIG. 12

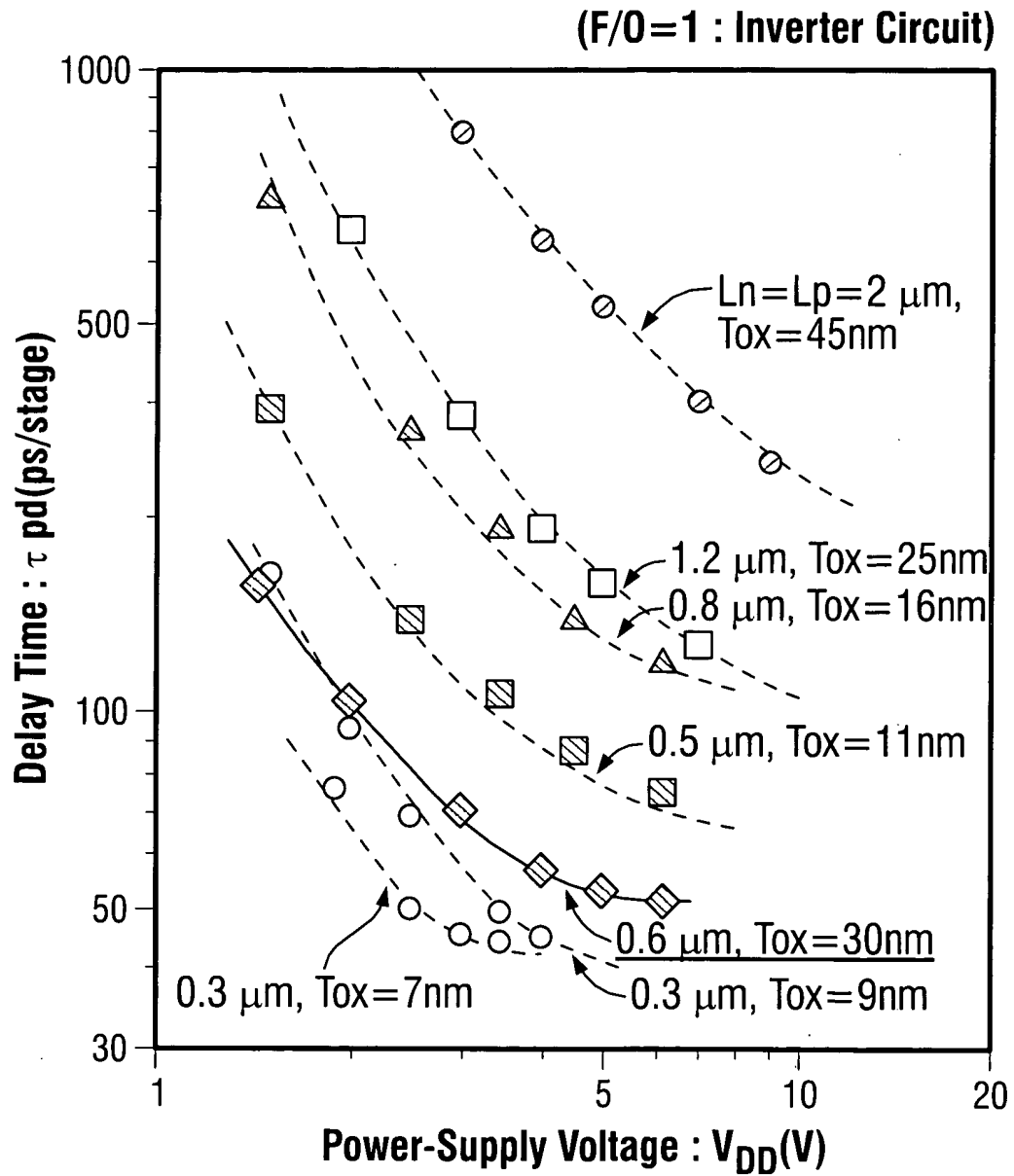


FIG. 13

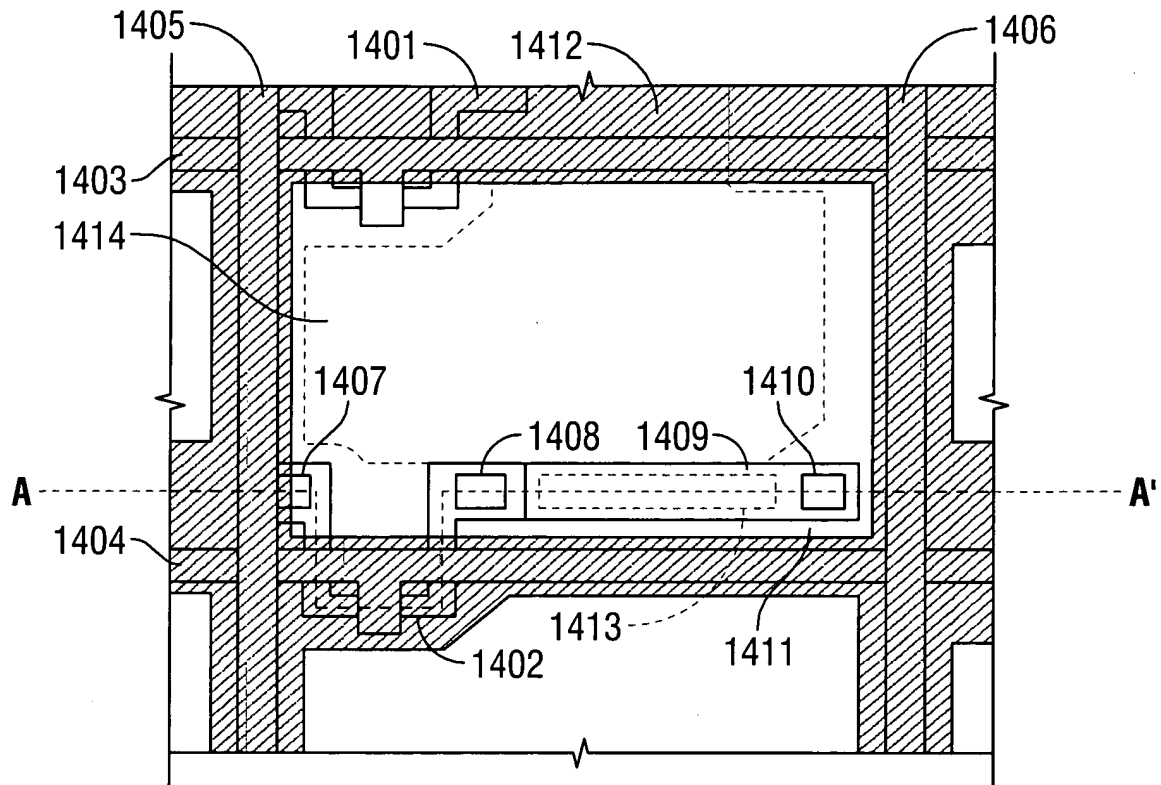


FIG. 14A

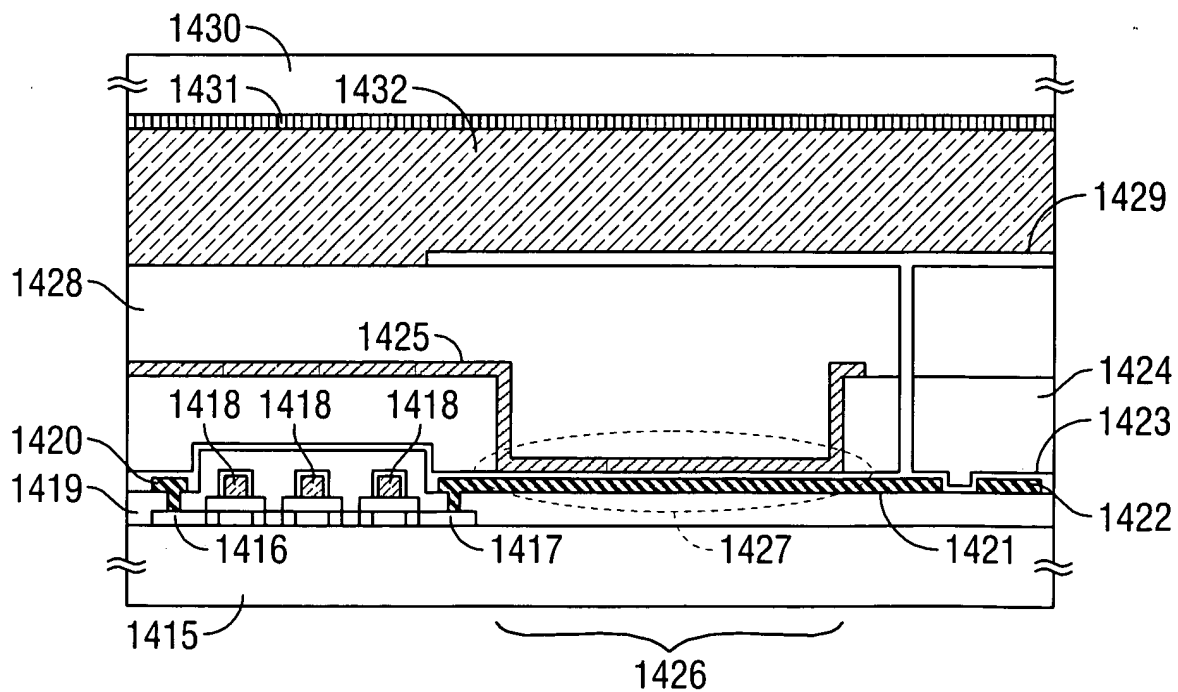


FIG. 14B

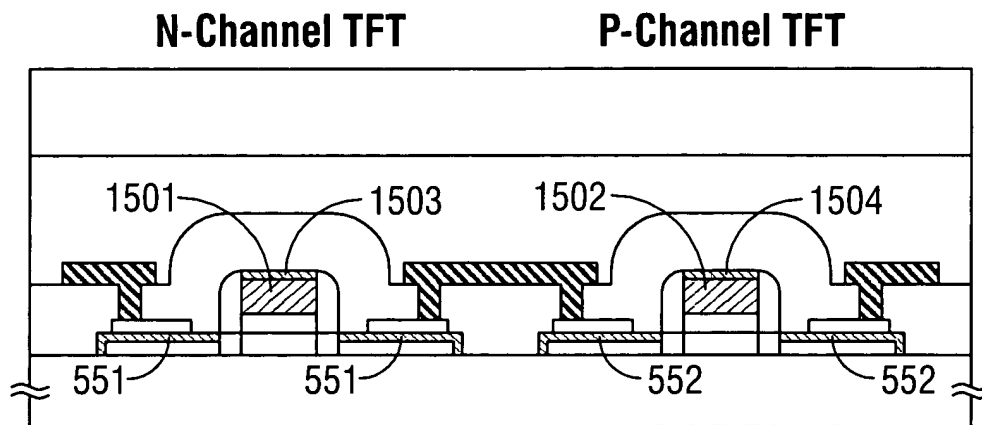


FIG. 15A

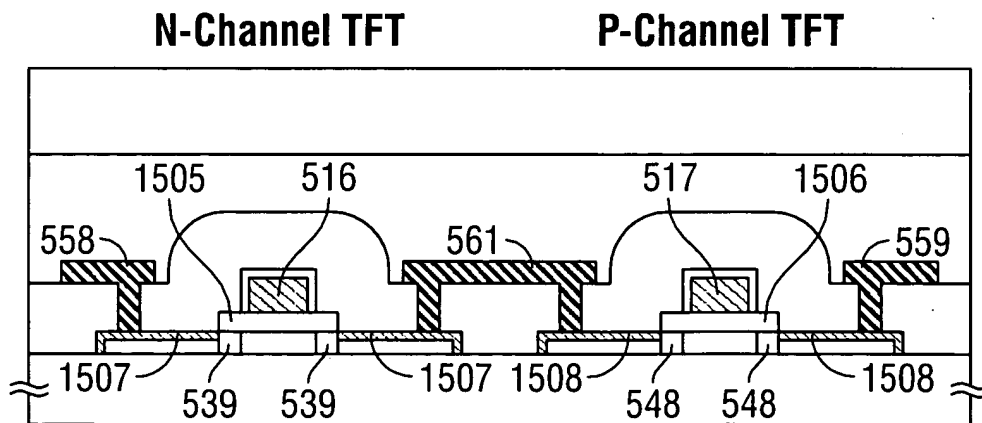


FIG. 15B

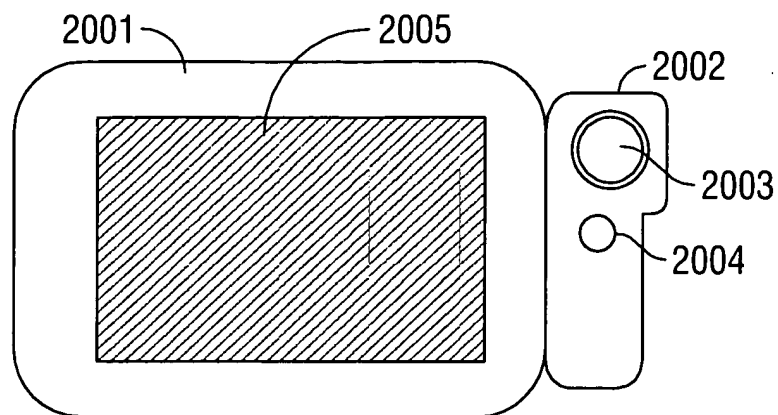


FIG. 16A

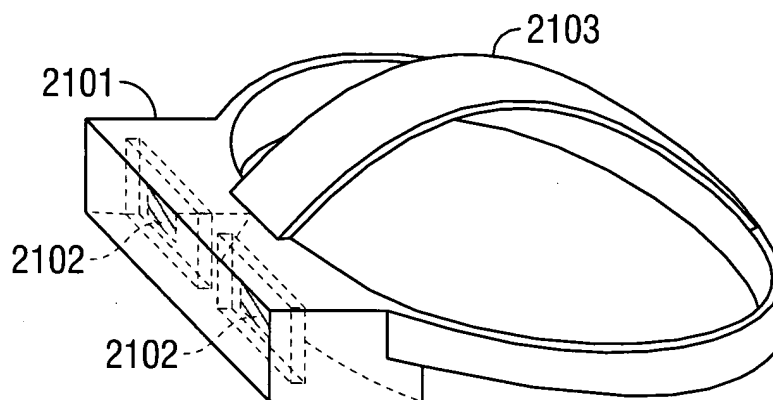


FIG. 16B

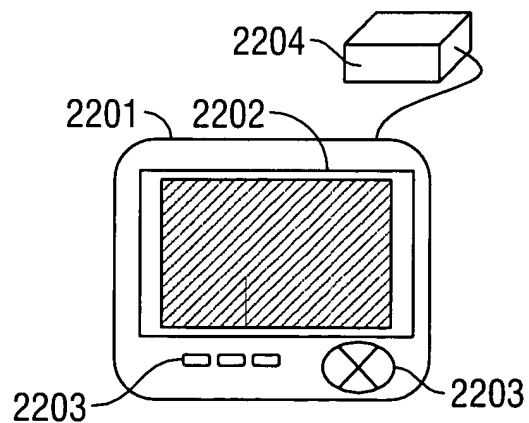


FIG. 16C

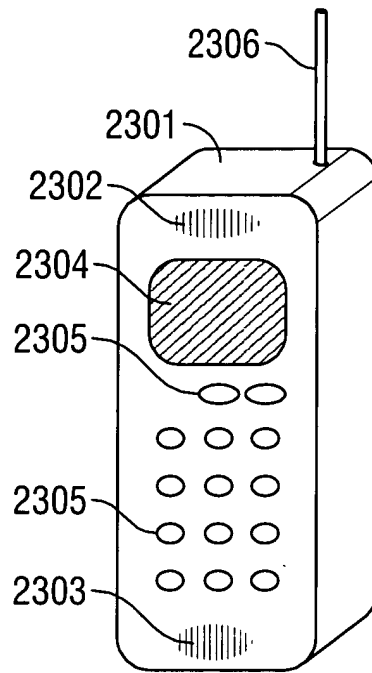


FIG. 16D

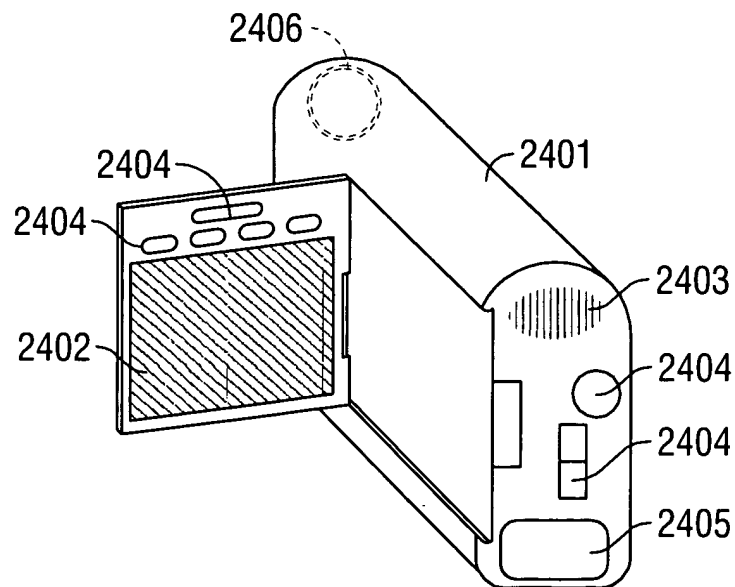


FIG. 16E

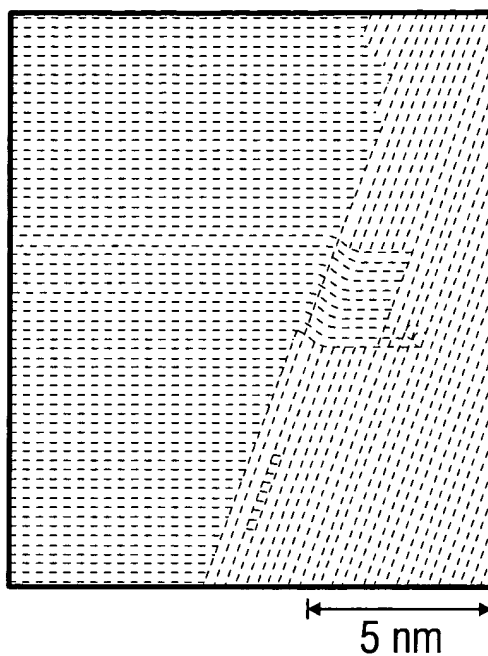


FIG. 17A

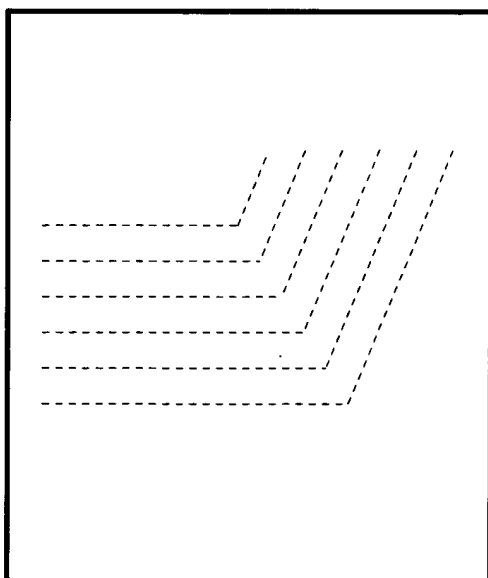


FIG. 17B

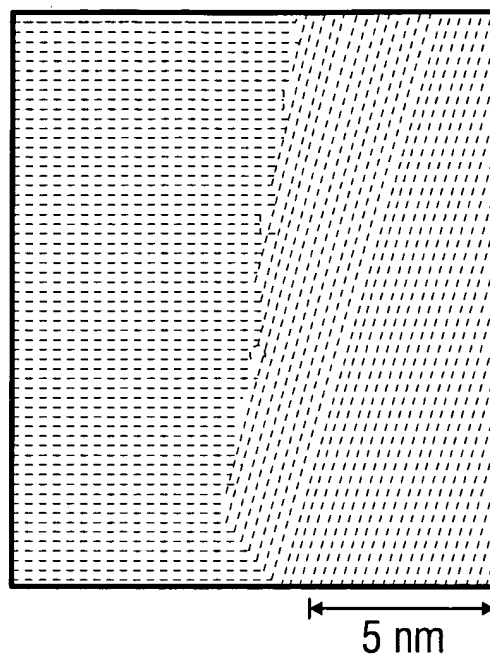


FIG. 17C

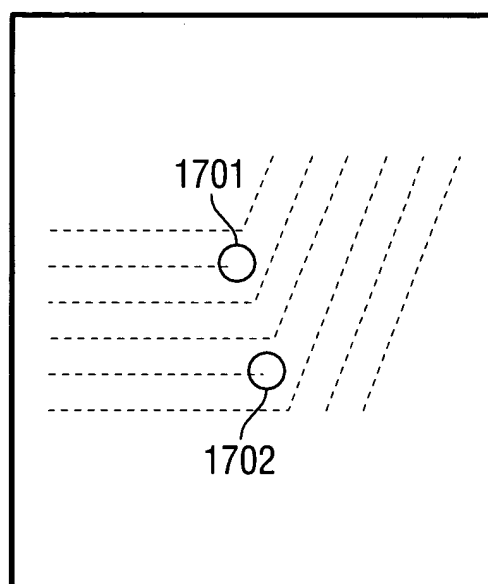


FIG. 17D

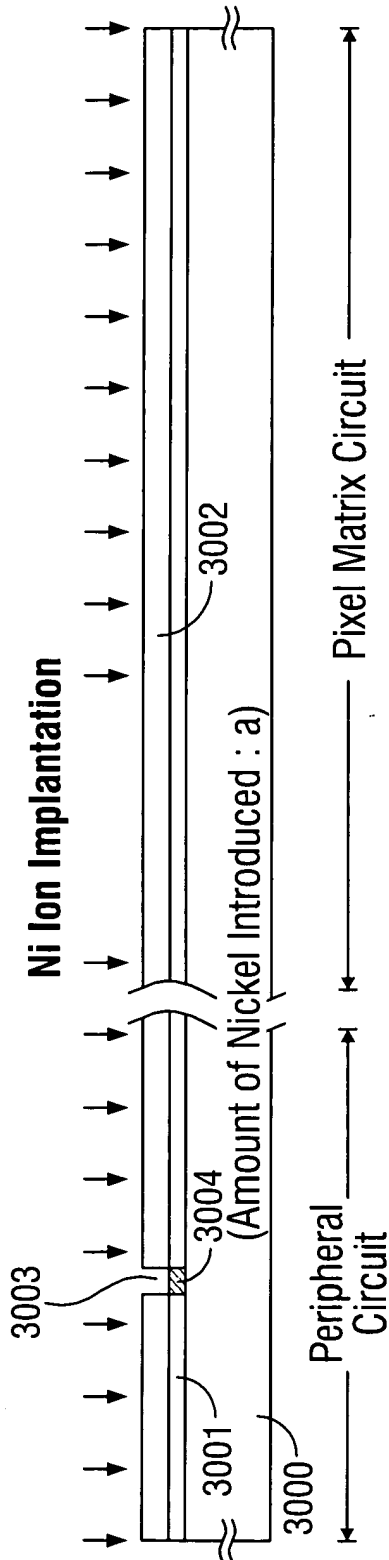


FIG. 18A

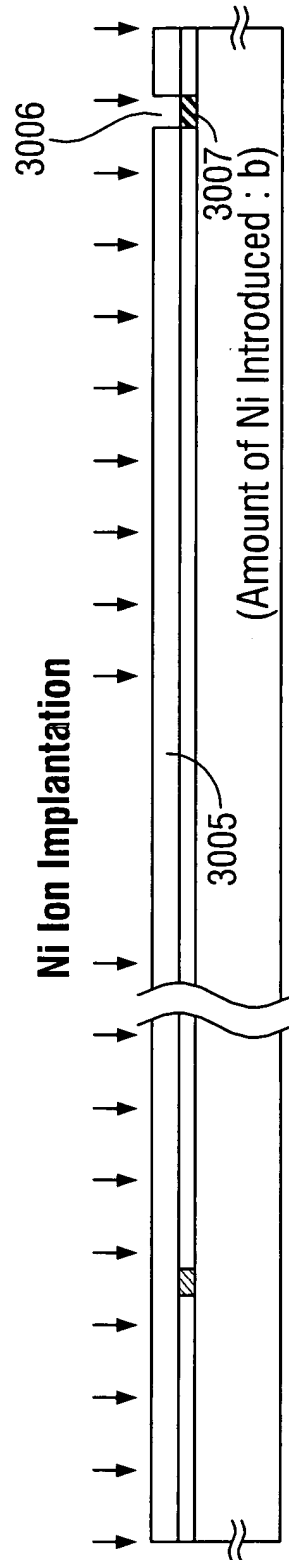


FIG. 18B

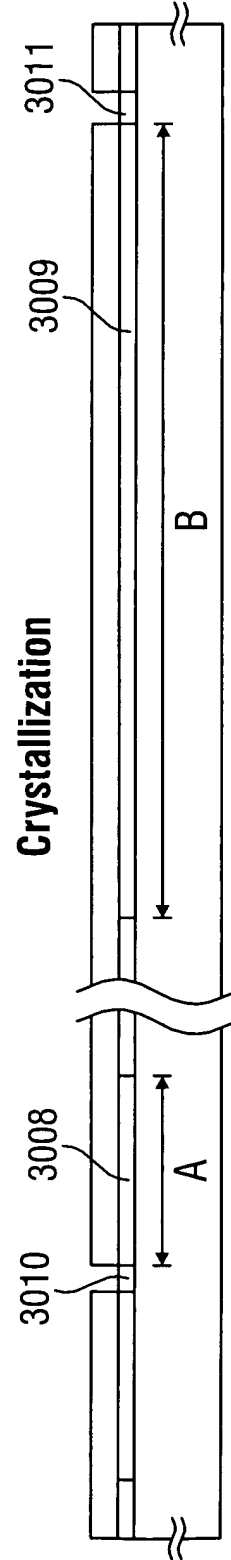


FIG. 18C

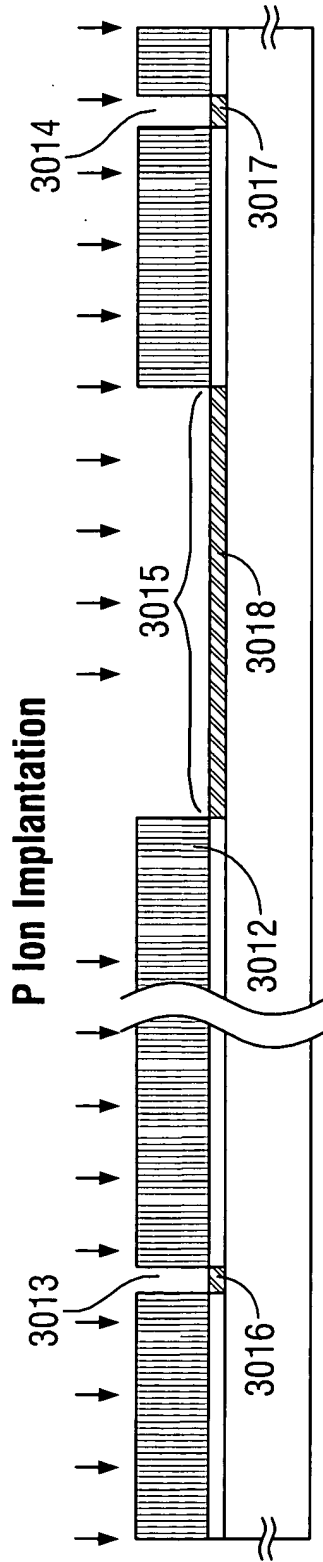


FIG. 19A

Gettering by Phosphorus Element

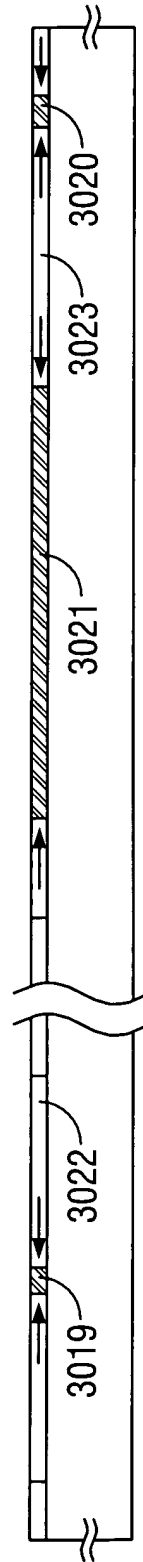


FIG. 19B

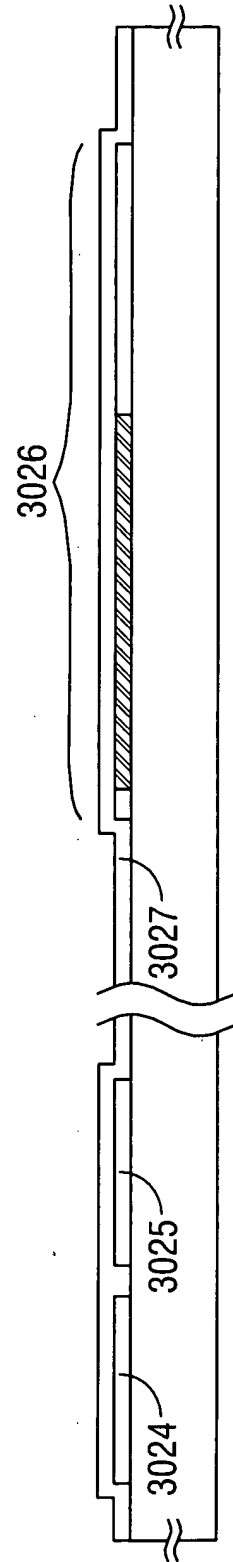


FIG. 19C

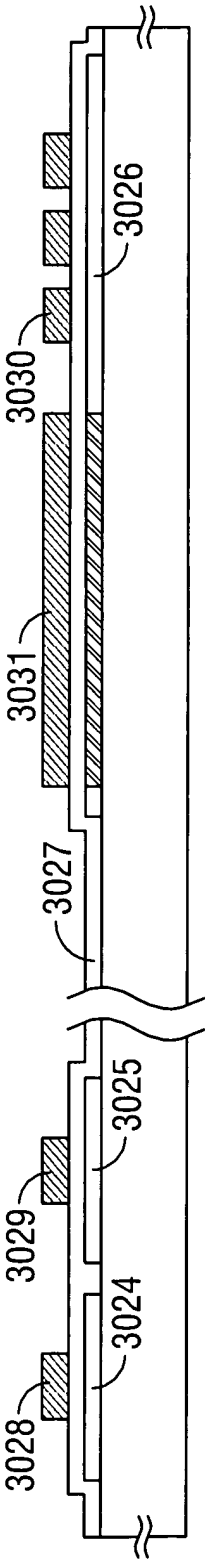


FIG. 20A

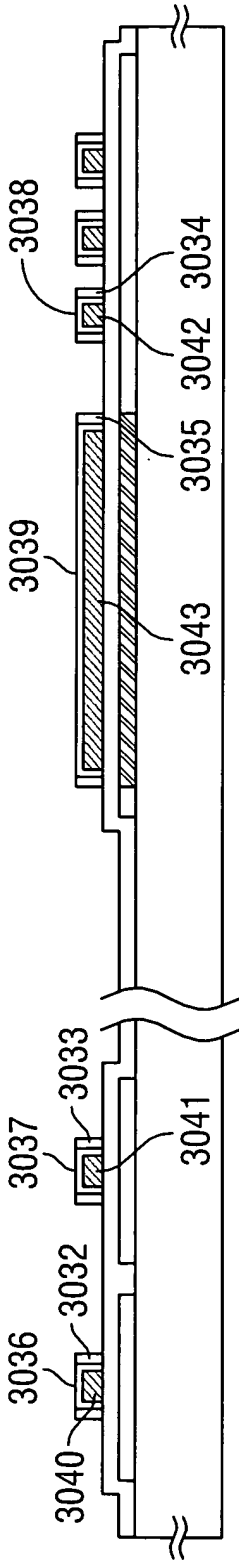


FIG. 20B

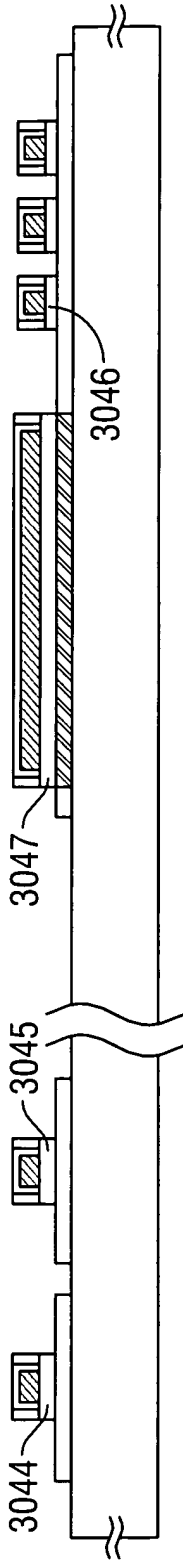


FIG. 20C

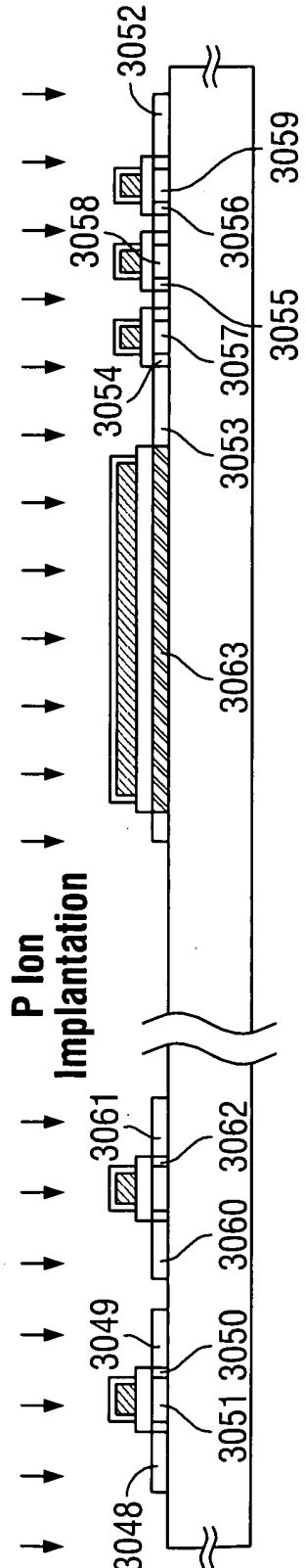


FIG. 20D

B Ion Implantation

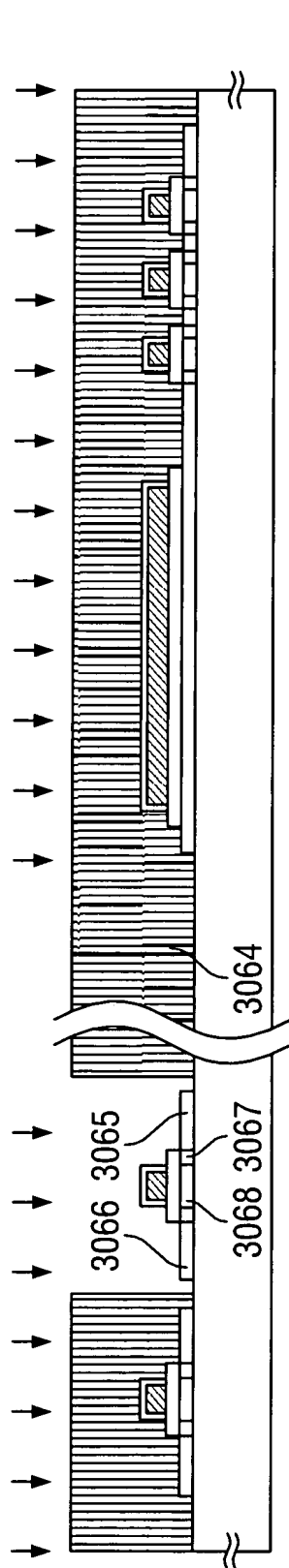


FIG. 21A

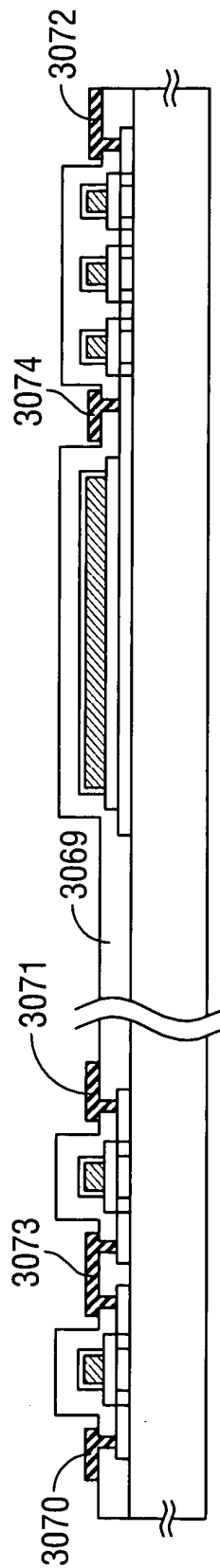


FIG. 21B

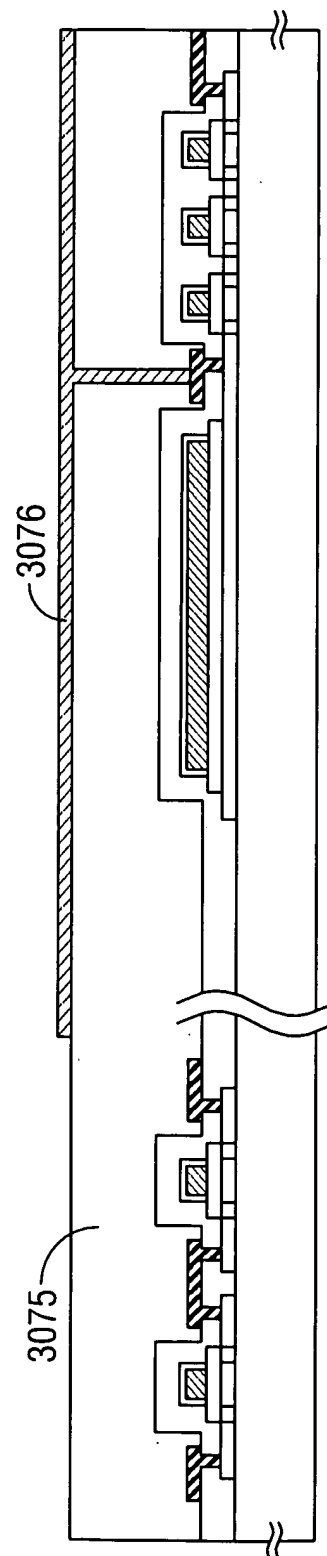


FIG. 21C

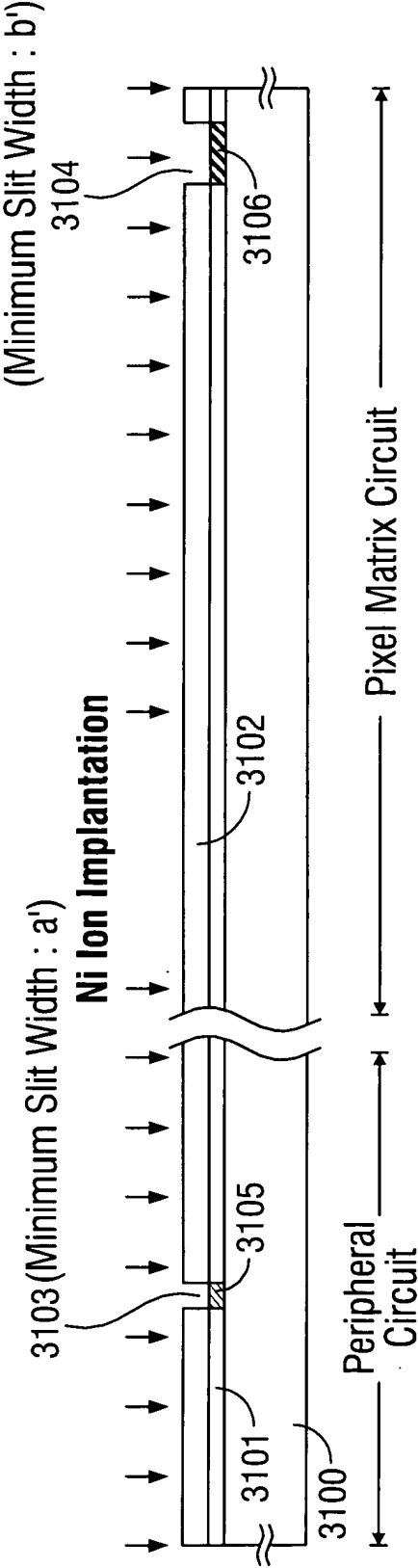


FIG. 22A

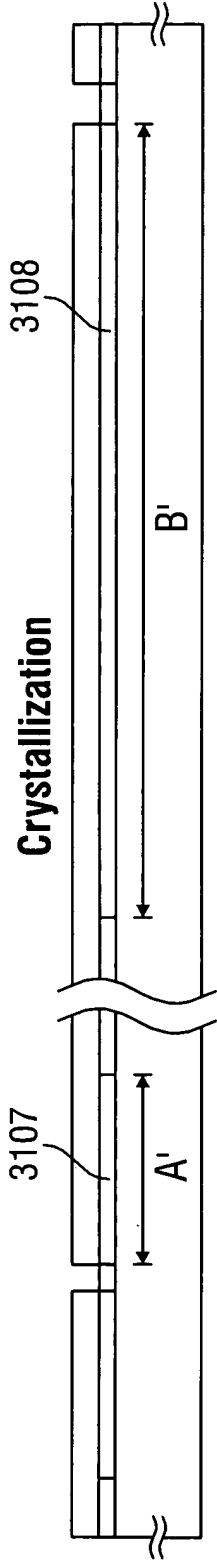


FIG. 22B

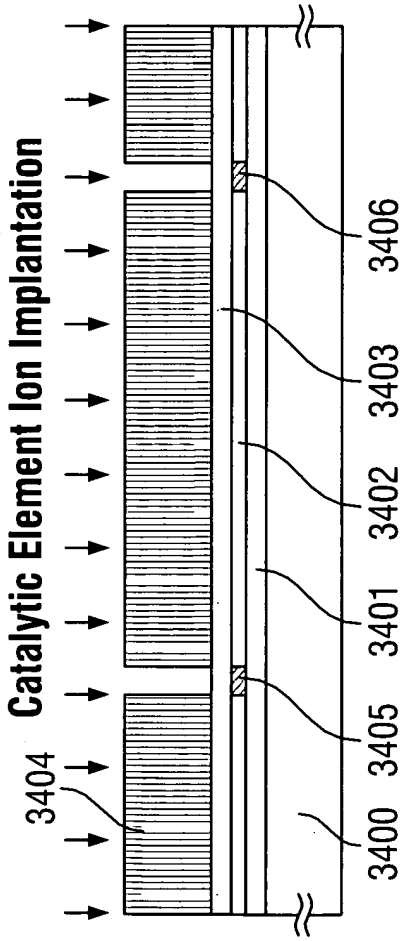


FIG. 23

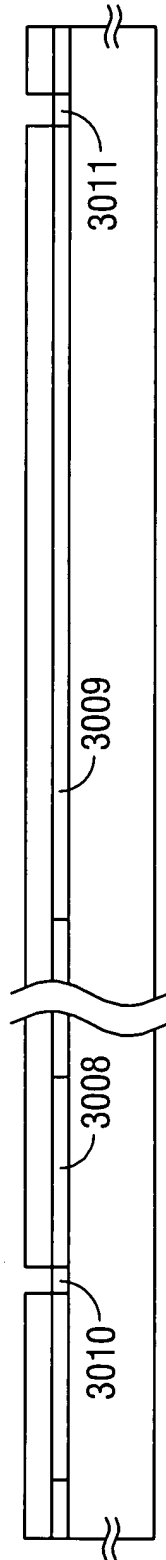


FIG. 24A

Gettering by Halogen Element

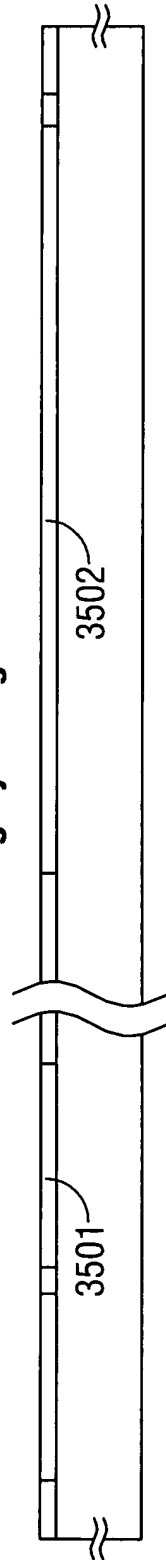


FIG. 24B

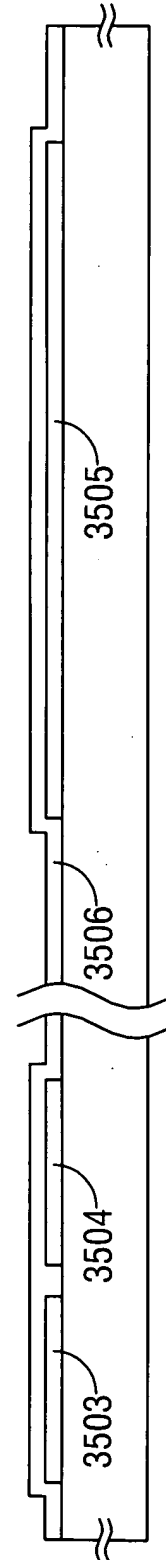


FIG. 24C

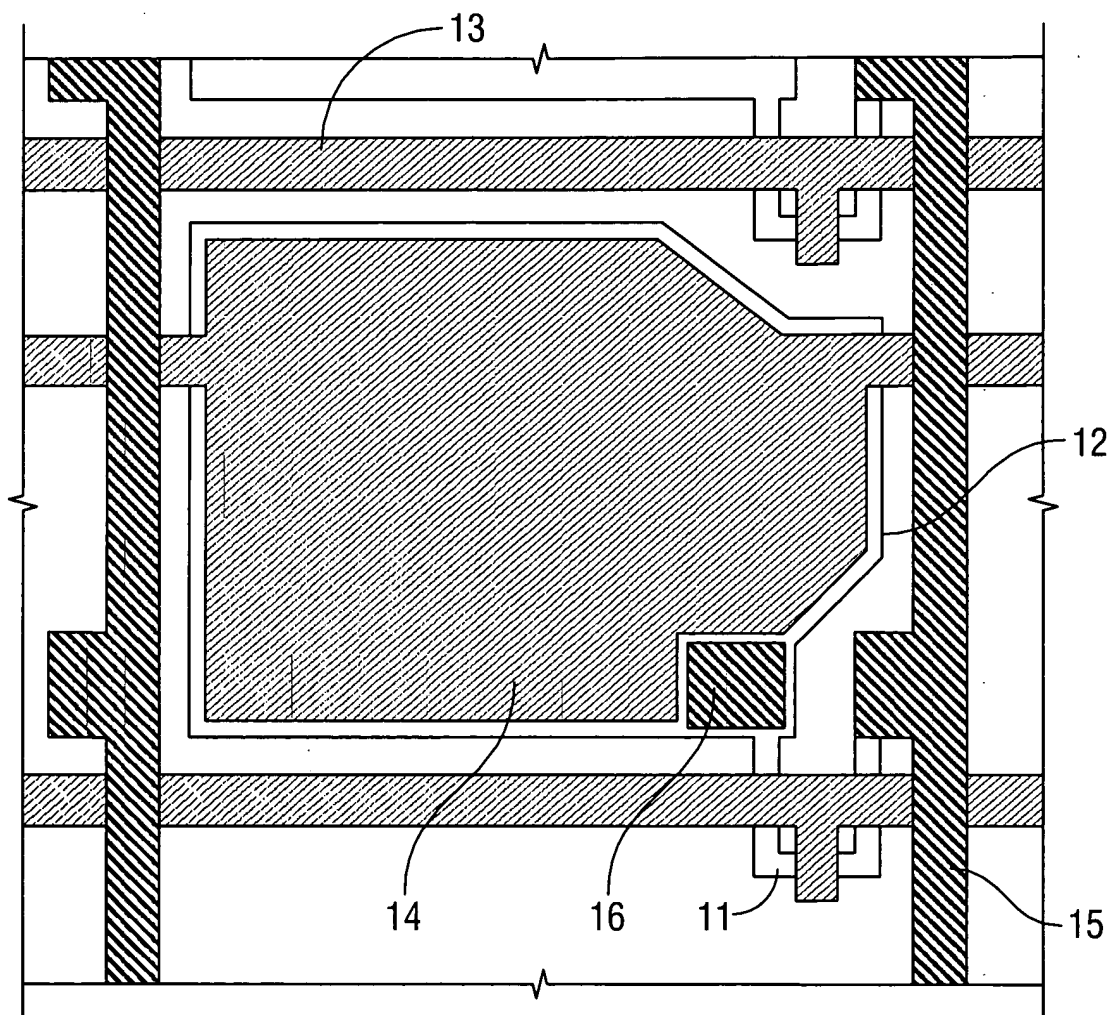


FIG. 25

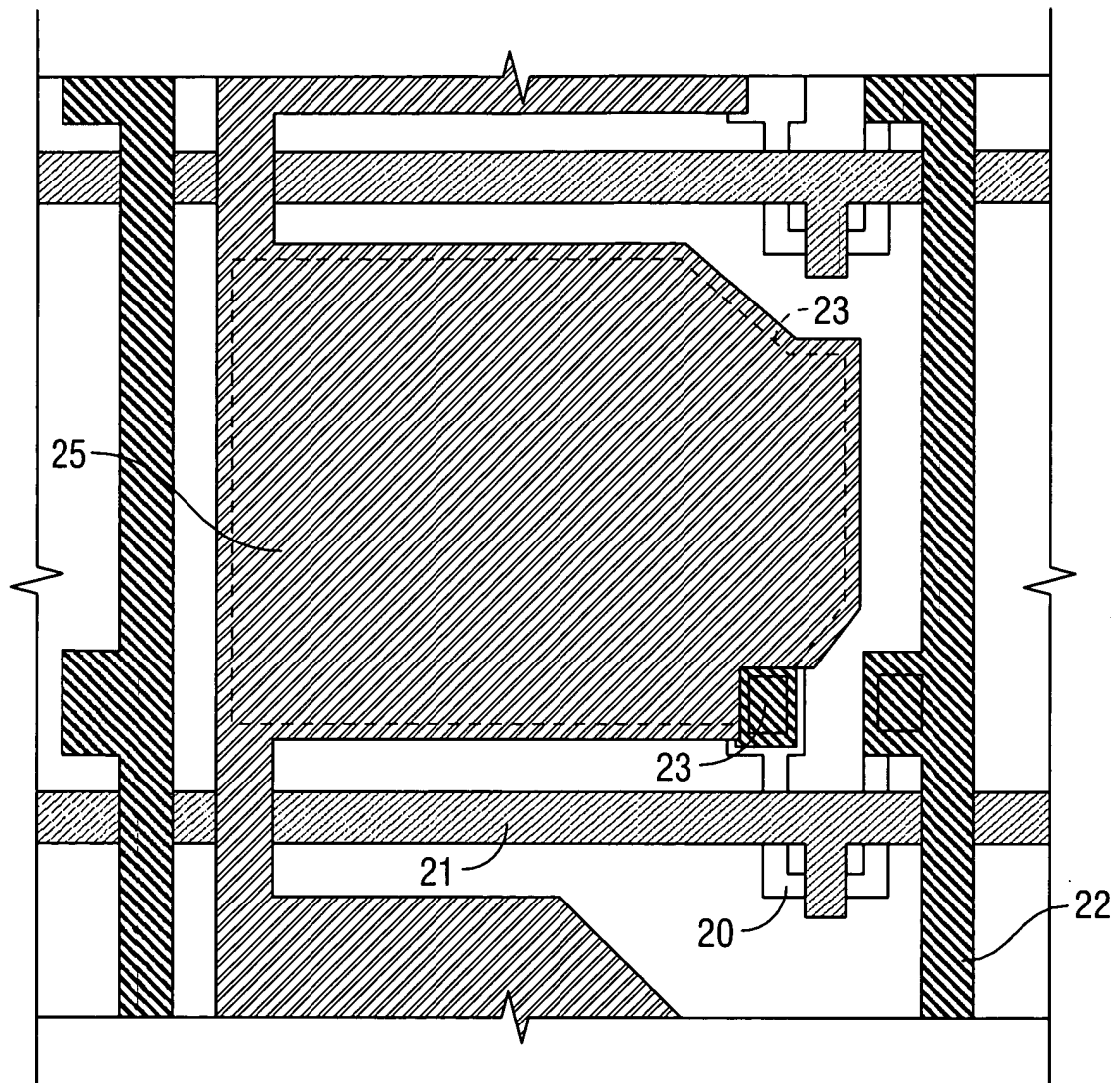


FIG. 26A

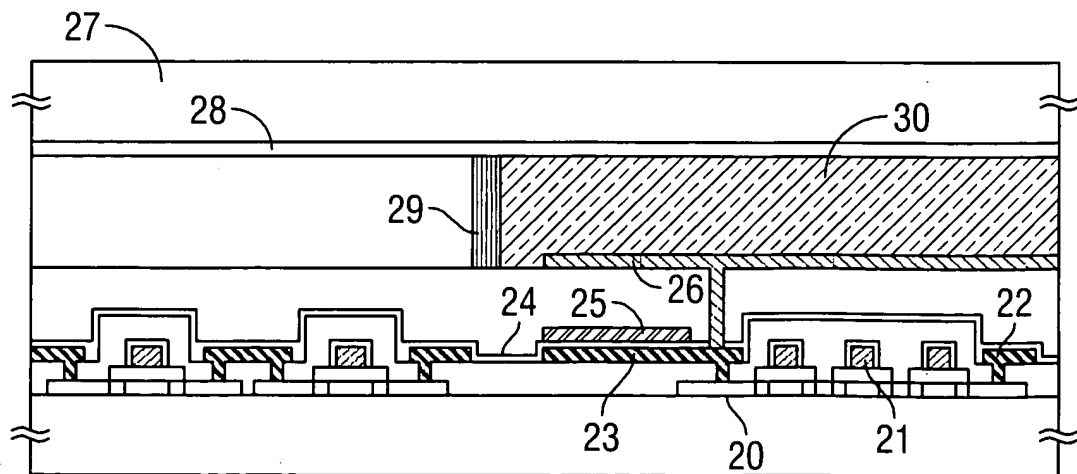


FIG. 26B